MOSFET – N-Channel, SUPERFET III, FRFET

650 V, 30 A, 110 m Ω

Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate.

Consequently, SUPERFET III MOSFET is very suitable for the various power systems for miniaturization and higher efficiency.

SUPERFET III FRFET MOSFET's optimized reverse recovery performance of body diode can remove additional component and improve system reliability.

Features

- 700 V @ $T_J = 150^{\circ}C$
- Typ. $R_{DS(on)} = 98 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. $Q_g = 62 \text{ nC}$)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 522 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

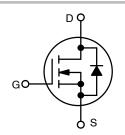
- Telecom / Server Power Supplies
- Industrial Power Supplies
- EV Charger
- UPS / Solar



ON Semiconductor®

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V _{DSS}	R _{DS(ON)} MAX I _D MAX	
650 V	110 mΩ @ 10 V	30 A

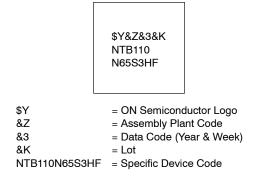


N-CHANNEL MOSFET



D²PAK (TO-263 3-Lead) CASE 418AJ

MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol	Parameter	Value	Unit	
V _{DSS}	Drain to Source Voltage		650	V
V _{GSS}	Gate to Source Voltage	– DC	±30	V
		– AC (f > 1 Hz)	±30	-
ID	Drain Current	– Continuous (T _C = 25°C)	30	A
		– Continuous (T _C = 100°C)	19.5	1
I _{DM}	Drain Current	– Pulsed (Note 1)	69	А
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		380	mJ
I _{AS}	Avalanche Current (Note 2)		4.4	A
E _{AR}	Repetitive Avalanche Energy (Note 1)		2.4	mJ
dv/dt	MOSFET dv/dt Peak Diode Recovery dv/dt (Note 3)		100	V/ns
			50	
PD	Power Dissipation	(T _C = 25°C)	240	W
		– Derate Above 25°C	1.92	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		–55 to +150	°C
ΤL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive rating: pulse-width limited by maximum junction temperature. 2. $I_{AS} = 4.4 \text{ A}$, $R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$. 3. $I_{SD} \le 15 \text{ A}$, di/dt $\le 100 \text{ A}/\mu\text{s}$, $V_{DD} \le 400 \text{ V}$, starting $T_J = 25^{\circ}C$.

THERMAL CHARACTERISTICS

	Symbol	Parameter	Value	Unit
ſ	$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	0.52	°C/W
	$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	45	

PACKAGE MARKING AND ORDERING INFORMATION

Part Number Top Marking		Package	Reel Size	Tape Width	Shipping [†]
NTB110N65S3HF	NTB110N65S3HF	D ² PAK	330 mm	24 mm	800 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

FI FCTRICAL CHARACTERISTICS (Tc = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARACT	ERISTICS	•	1		1	
BV _{DSS}	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 1 \text{ mA}, \text{ T}_{J} = 25^{\circ}\text{C}$	650	-	-	V
		$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 1 \text{ mA}, \text{ T}_{J} = 150^{\circ}\text{C}$	700	-	-	V
$\Delta \text{BV}_{\text{DSS}} / \Delta \text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 15 mA, Referenced to 25°C	-	0.64	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	10	μA
		$V_{DS} = 520 \text{ V}, \text{ T}_{C} = 125^{\circ}\text{C}$	-	97	_	
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 30$ V, $V_{DS} = 0$ V	-	-	±100	nA
ON CHARACTE	RISTICS					
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 0.74 \text{ mA}$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 15 A	-	98	110	mΩ
9 FS	Forward Transconductance	V _{DS} = 20 V, I _D = 15 A	-	18	-	S
DYNAMIC CHA	RACTERISTICS	•				
C _{iss}	Input Capacitance	V_{DS} = 400 V, V_{GS} = 0 V, f = 1 MHz	-	2635	-	pF
C _{oss}	Output Capacitance		_	52	_	pF
C _{oss(eff.)}	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	522	-	pF
C _{oss(er.)}	Energy Related Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	91	-	pF
Q _{g(tot)}	Total Gate Charge at 10V	$V_{DS} = 400 \text{ V}, \text{ I}_{D} = 15 \text{ A}, \text{ V}_{GS} = 10 \text{ V}$	-	62	_	nC
Q _{gs}	Gate to Source Gate Charge	(Note 4)	-	18	-	nC
Q _{gd}	Gate to Drain "Miller" Charge		-	25	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	4.6	-	Ω
SWITCHING CH	IARACTERISTICS					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, I_D = 15 \text{ A},$	-	24	_	ns
t _r	Turn-On Rise Time	V _{GS} = 10 V, R _g = 4.7 Ω (Note 4)	_	25	-	ns
t _{d(off)}	Turn-Off Delay Time		-	85	-	ns
t _f	Turn-Off Fall Time		-	25	-	ns
SOURCE-DRAII	N DIODE CHARACTERISTICS	1	1	1	1	
I _S	Maximum Continuous Source to Drain Diode Forward Current		-	-	30	Α
I _{SM}	Maximum Pulsed Source to Drain Diode Forward Current		-	-	69	Α
V _{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 15 A	-	-	1.3	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 15 A,	-	95	-	ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt = 100 A/µs	_	371	_	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Essentially independent of operating temperature typical characteristics.

TYPICAL PERFORMANCE CHARACTERISTICS

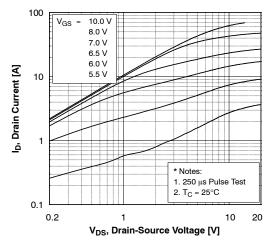


Figure 1. On-Region Characteristics

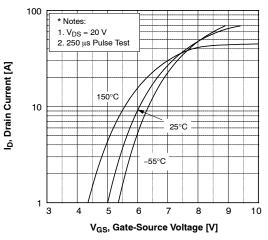


Figure 2. Transfer Characteristics

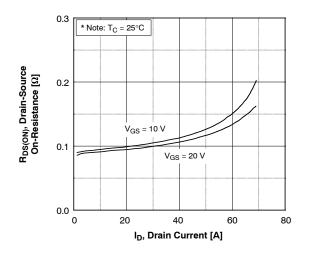


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

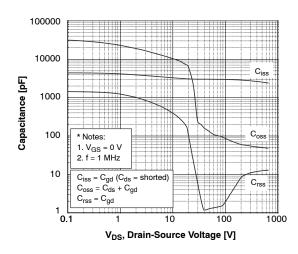


Figure 5. Capacitance Characteristics

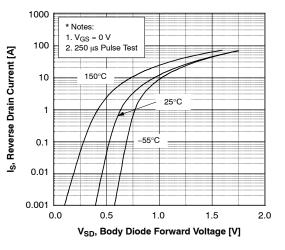


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

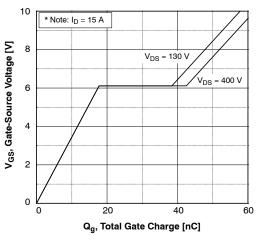
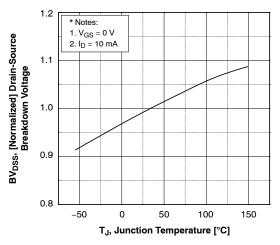


Figure 6. Gate Charge Characteristics

TYPICAL PERFORMANCE CHARACTERISTICS (Continued)





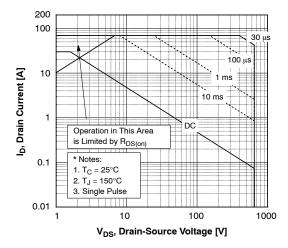


Figure 9. Maximum Safe Operation Area

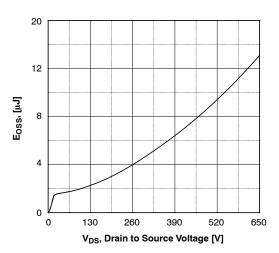


Figure 11. E_{OSS} vs. Drain to Source Voltage

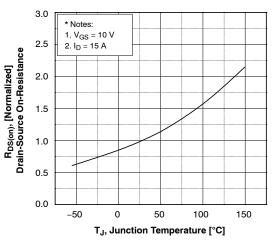


Figure 8. On-Resistance Variant vs. Temperature

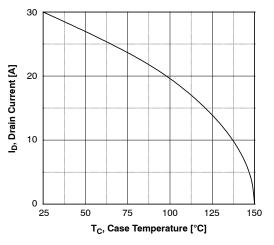


Figure 10. Maximum Drain Current vs. Case Temperature

TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

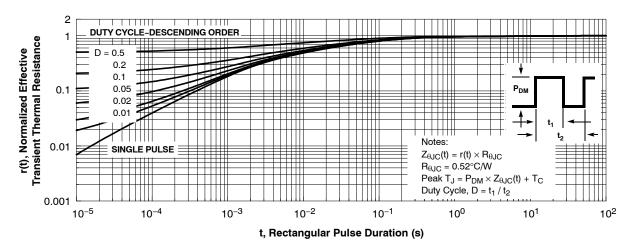


Figure 12. Transient Thermal Response Curve

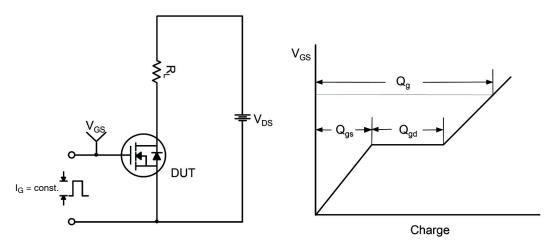


Figure 13. Gate Charge Test Circuit & Waveform

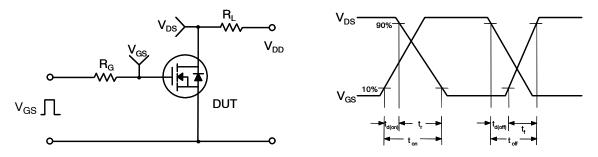


Figure 14. Resistive Switching Test Circuit & Waveforms

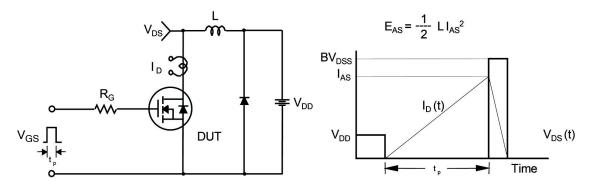


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

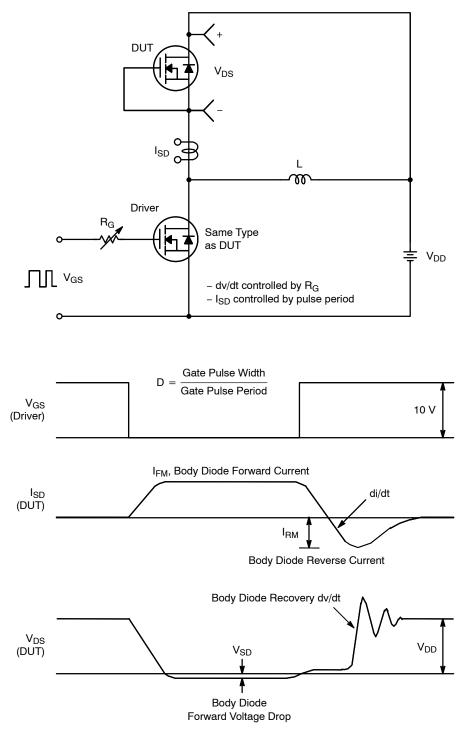
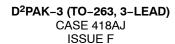


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

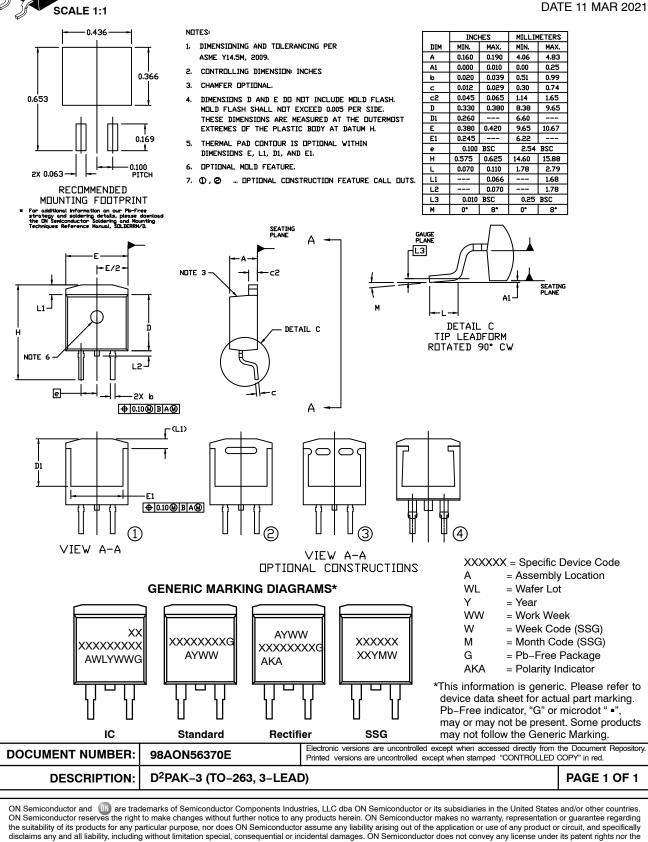
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MECHANICAL CASE OUTLINE PACKAGE DIMENSIONS









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